| | Application No. | Applicant(s) |
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| Notice of Allowability | 09/818,666 Examiner | FULFORD ET AL. Art Unit |
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| | Binh X Tran | 1765 |
| The MAILING DATE of this communication appear All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOT the Office or upon petition by the applicant. See 37 CFR 1.313 | (OR REMAINS) CLOSED in this or other appropriate communicating GHTS. This application is subjection. | application. If not included tion will be mailed in due course. THIS |
| 1. This communication is responsive to 01-14-2004. | | |
| 2. ☑ The allowed claim(s) is/are <u>1-32,41 and 42</u> . | | |
| 3. The drawings filed on 27 March 2001 are accepted by the Examiner. | | |
| 4. ☐ Acknowledgment is made of a claim for foreign priority una) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents have 2. ☐ Certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority do International Bureau (PCT Rule 17.2(a)). * Certified copies not received: | been received. been received in Application No |) |
| Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. | | |
| 5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient. | | |
| 6. CORRECTED DRAWINGS (as "replacement sheets") must (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner' Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the state of the sheet | son's Patent Drawing Review(P s Amendment / Comment or in th .84(c)) should be written on the dr | ne Office action of awings in the front (not the back) of |
| DEPOSIT OF and/or INFORMATION about the depo- attached Examiner's comment regarding REQUIREMENT | SIT OF BIOLOGICAL MATERIA FOR THE DEPOSIT OF BIOLOG | AL must be submitted. Note the GICAL MATERIAL. |
| Attachment(s) 1. Notice of References Cited (PTO-892) 2. Notice of Draftperson's Patent Drawing Review (PTO-948) 3. Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date | 6. Interview Summ Paper No./Mail 7. Examiner's Ame | Date <u>20040202</u> . endment/Comment |
| Examiner's Comment Regarding Requirement for Deposit of Biological Material | 8. ⊠ Examiner's Stat 9. ☐ Other | ement of Reasons for Allowance |
| O, Diological Material | | NADINE G. NORTON ERVISORY PATENT EXAMINER |

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EXAMINER'S AMENDMENT

- 1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- 2. Authorization for this examiner's amendment was given in a telephone interview with Ruben S. Bains on 02-02-2004.
- 3. The application has been amended as follows:

In the claims

Please cancel claims 33-40 as drawn to the non-elected invention.

Allowable Subject Matter

- 5. Claims 1-32, 41-42 are allowed.
- 6. The following is an examiner's statement of reasons for allowance: Respect to claims 1-12, the reasons for allowance has been discussed in previous office action. Respect to claims 13-32, , 41-42, the cited prior arts fail to suggest or discloses the step of measuring the depth of the etch at two different locations and using the depths to vary the temperature in the subsequently processed semiconducting substrate in conjunction with all other limitations in the claims. The closest prior art (Bukhman et al.) teaches to measure an initial thickness of the wafer before any etching step and a subsequent thickness of the wafer after the etching step.

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7. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Binh X Tran whose telephone number is (571) 272-1469. The examiner can normally be reached on Monday-Thursday and every other Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nadine G Norton can be reached on (571) 272-1465. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Binh X. Tran

NADINE G. NORTON SUPERVISORY TYAMINER